

International Rectifier

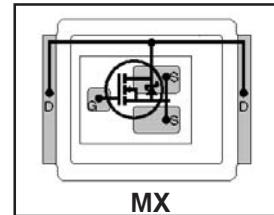
- RoHS Compliant Containing No Lead and Bromide ①
- Integrated Monolithic Schottky Diode
- Low Profile (<0.7 mm)
- Dual Sided Cooling Compatible ①
- Ultra Low Package Inductance
- Optimized for High Frequency Switching ①
- Ideal for CPU Core DC-DC Converters
- Optimized for Sync. FET socket of Sync. Buck Converter ①
- Low Conduction and Switching Losses
- Compatible with existing Surface Mount Techniques ①
- 100% R_g tested

IRF6797MPbF IRF6797MTRPbF

HEXFET® Power MOSFET plus Schottky Diode ②

Typical values (unless otherwise specified)

V _{DSS}	V _{GS}	R _{DS(on)}	R _{DS(on)}		
25V max	±20V max	1.1mΩ@ 10V	1.8mΩ@ 4.5V		
Q _{g tot}	Q _{gd}	Q _{gs2}	Q _{rr}	Q _{oss}	V _{gs(th)}
45nC	13nC	6.2nC	38nC	38nC	1.8V



Applicable DirectFET Outline and Substrate Outline (see p.7,8 for details) ①

SQ	SX	ST	MQ	MX	MT	MP		
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Description

The IRF6797MPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET™ packaging to achieve the lowest on-state resistance in a package that has the footprint of a SO-8 and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques. Application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems, improving previous best thermal resistance by 80%.

The IRF6797MPbF balances industry leading on-state resistance while minimizing gate charge along with ultra low package inductance to reduce both conduction and switching losses. This part contains an integrated Schottky diode to reduce the Q_{rr} of the body drain diode further reducing the losses in a Synchronous Buck circuit. The reduced losses make this product ideal for high frequency/high efficiency DC-DC converters that power high current loads such as the latest generation of microprocessors. The IRF6797MPbF has been optimized for parameters that are critical in synchronous buck converter's Sync FET sockets.

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	25	V
V _{GS}	Gate-to-Source Voltage	±20	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V ③	36	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V ③	29	A
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ④	210	
I _{DM}	Pulsed Drain Current ⑤	300	
E _{AS}	Single Pulse Avalanche Energy ⑥	260	mJ
I _{AR}	Avalanche Current ⑤	30	A

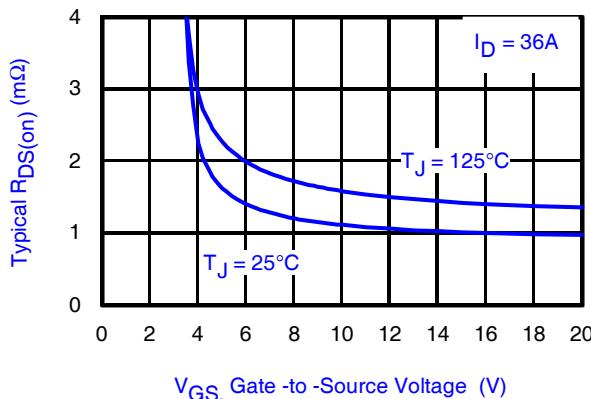


Fig 1. Typical On-Resistance vs. Gate Voltage

Notes:

- ① Click on this section to link to the appropriate technical paper.
- ② Click on this section to link to the DirectFET Website.
- ③ Surface mounted on 1 in. square Cu board, steady state.

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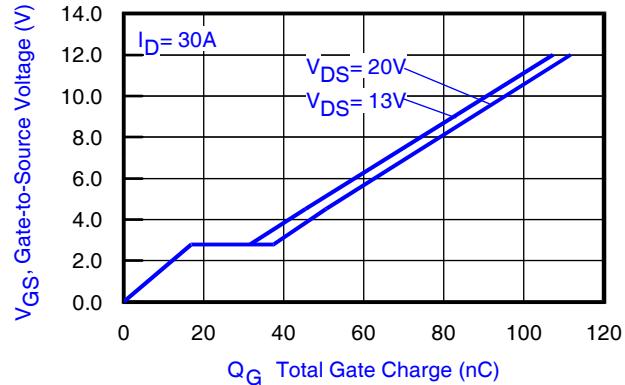


Fig 2. Typical Total Gate Charge vs. Gate-to-Source Voltage

- ④ T_C measured with thermocouple mounted to top (Drain) of part.
- ⑤ Repetitive rating; pulse width limited by max. junction temperature.
- ⑥ Starting T_J = 25°C, L = 0.57mH, R_G = 25Ω, I_{AS} = 30A.

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	25	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = 1.0\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	10	—	$\text{mV}/^\circ\text{C}$	Reference to 25°C , $I_D = 10\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	1.1	1.4	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}$, $I_D = 38\text{A}$ ⑦
		—	1.8	2.4		$V_{\text{GS}} = 4.5\text{V}$, $I_D = 30\text{A}$ ⑦
$V_{\text{GS(th)}}$	Gate Threshold Voltage	1.35	1.8	2.35	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 150\mu\text{A}$
$\Delta V_{\text{GS(th)}}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-4.6	—	$\text{mV}/^\circ\text{C}$	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 10\text{mA}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	500	μA	$V_{\text{DS}} = 20\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	5.0	mA	$V_{\text{DS}} = 20\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
g_{fs}	Forward Transconductance	130	—	—	S	$V_{\text{DS}} = 13\text{V}$, $I_D = 30\text{A}$
Q_g	Total Gate Charge	—	45	68	nC	$V_{\text{DS}} = 13\text{V}$ $V_{\text{GS}} = 4.5\text{V}$ $I_D = 30\text{A}$ See Fig. 15
$Q_{\text{gs}1}$	Pre-V _{th} Gate-to-Source Charge	—	12	—		
$Q_{\text{gs}2}$	Post-V _{th} Gate-to-Source Charge	—	6.2	—		
Q_{gd}	Gate-to-Drain Charge	—	13	—		
Q_{godr}	Gate Charge Overdrive	—	14	—		
Q_{sw}	Switch Charge ($Q_{\text{gs}2} + Q_{\text{gd}}$)	—	19.2	—		
Q_{oss}	Output Charge	—	38	—	nC	$V_{\text{DS}} = 16\text{V}$, $V_{\text{GS}} = 0\text{V}$
R_G	Gate Resistance	—	1.3	2.2	Ω	
$t_{\text{d(on)}}$	Turn-On Delay Time	—	22	—	ns	$V_{\text{DD}} = 13\text{V}$, $V_{\text{GS}} = 4.5\text{V}$ ⑦ $I_D = 30\text{A}$ $R_G = 1.8\Omega$ See Fig. 17
t_r	Rise Time	—	32	—		
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	20	—		
t_f	Fall Time	—	15	—		
C_{iss}	Input Capacitance	—	5790	—	pF	$V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 13\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	1790	—		
C_{rss}	Reverse Transfer Capacitance	—	720	—		

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	36	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ⑤	—	—	300		
V_{SD}	Diode Forward Voltage	—	—	0.65	V	$T_J = 25^\circ\text{C}$, $I_S = 30\text{A}$, $V_{\text{GS}} = 0\text{V}$ ⑦
t_{rr}	Reverse Recovery Time	—	30	45	ns	$T_J = 25^\circ\text{C}$, $I_F = 30\text{A}$
Q_{rr}	Reverse Recovery Charge	—	38	57	nC	$dI/dt = 200\text{A}/\mu\text{s}$ ⑦

Notes:

⑦ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.

Absolute Maximum Ratings

	Parameter	Max.	Units
P _D @ T _A = 25°C	Power Dissipation ③	2.8	
P _D @ T _A = 70°C	Power Dissipation ③	1.8	
P _D @ T _C = 25°C	Power Dissipation ④	89	
T _P	Peak Soldering Temperature	270	°C
T _J	Operating Junction and Storage Temperature Range	-40 to + 150	
T _{STG}			

Thermal Resistance

	Parameter	Typ.	Max.	Units
R _{θJA}	Junction-to-Ambient ③⑩	—	45	
R _{θJA}	Junction-to-Ambient ⑧⑩	12.5	—	
R _{θJA}	Junction-to-Ambient ⑨⑩	20	—	°C/W
R _{θJC}	Junction-to-Case ④⑩	—	1.4	
R _{θJ-PCB}	Junction-to-PCB Mounted	1.0	—	
	Linear Derating Factor ③	0.022		W/°C

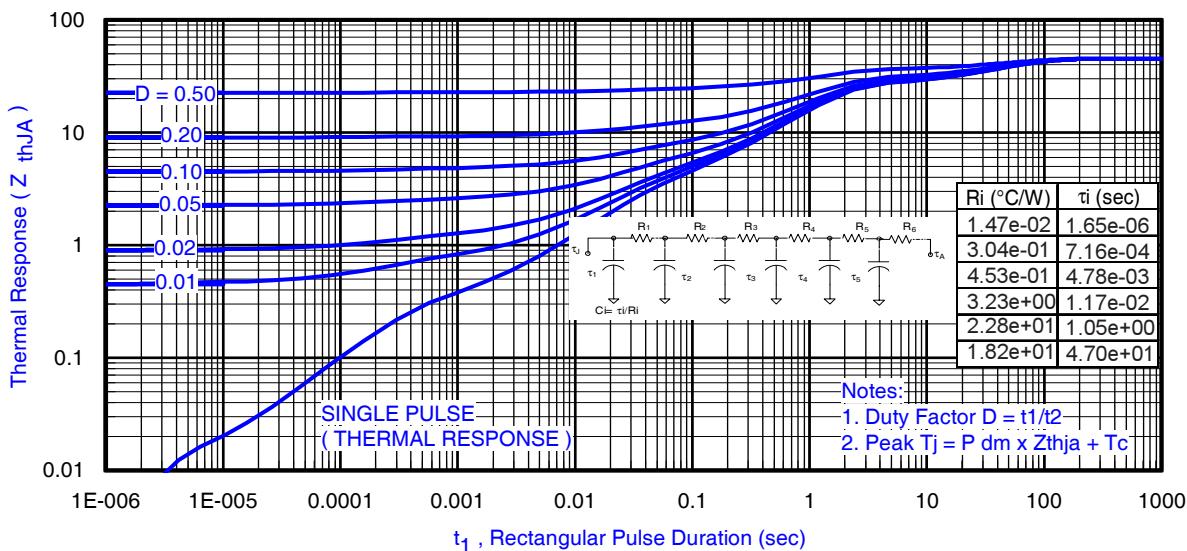


Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient ③
(At lower pulse widths Z_{θJA} & Z_{θJC} are combined)

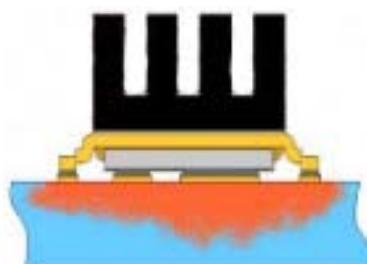
Notes:

⑧ Used double sided cooling , mounting pad with large heatsink. ⑩ R_θ is measured at T_j of approximately 90°C.

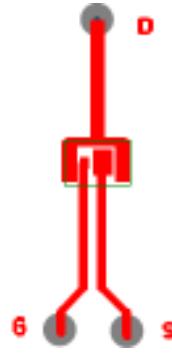
⑨ Mounted on minimum footprint full size board with metalized back and with small clip heatsink.



③ Surface mounted on 1 in. square Cu (still air).



⑨ Mounted to a PCB with small clip heatsink (still air)



⑨ Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air)

IRF6797MTRPbF

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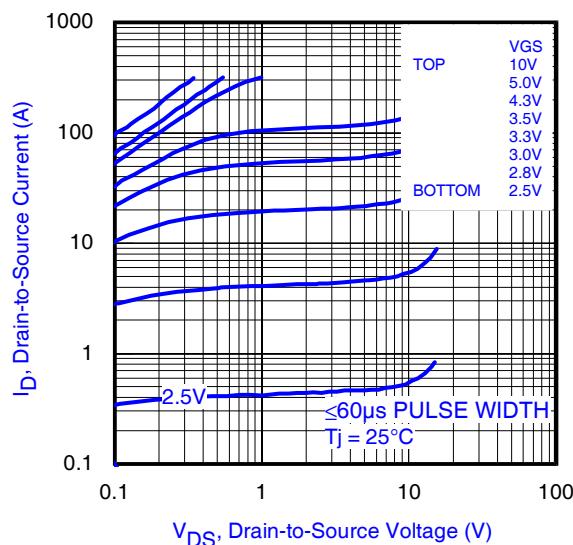


Fig 4. Typical Output Characteristics

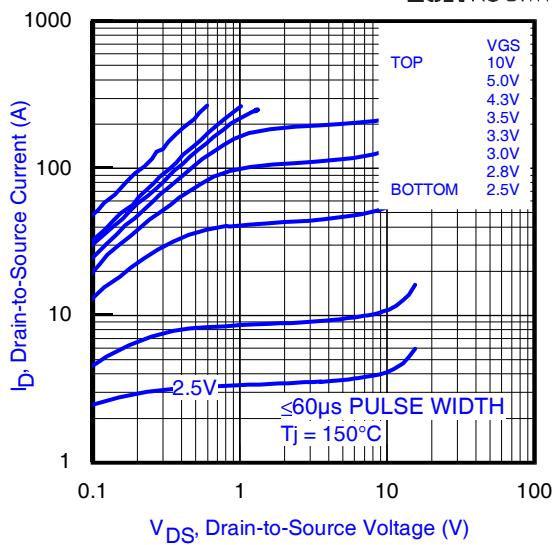


Fig 5. Typical Output Characteristics

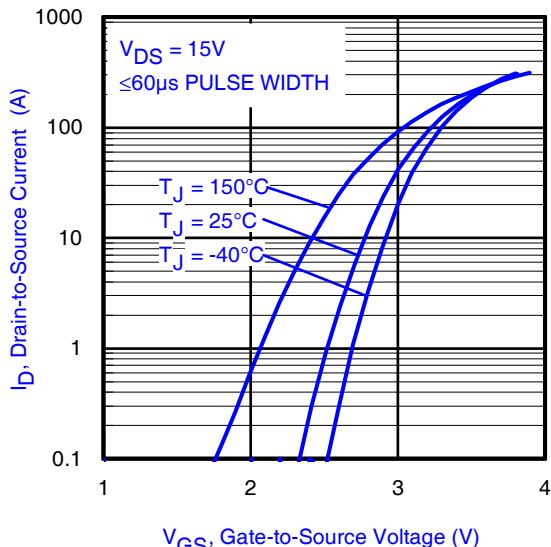


Fig 6. Typical Transfer Characteristics

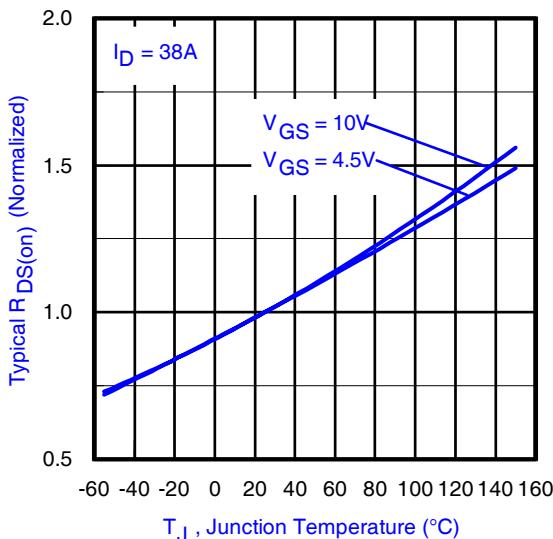


Fig 7. Normalized On-Resistance vs. Temperature

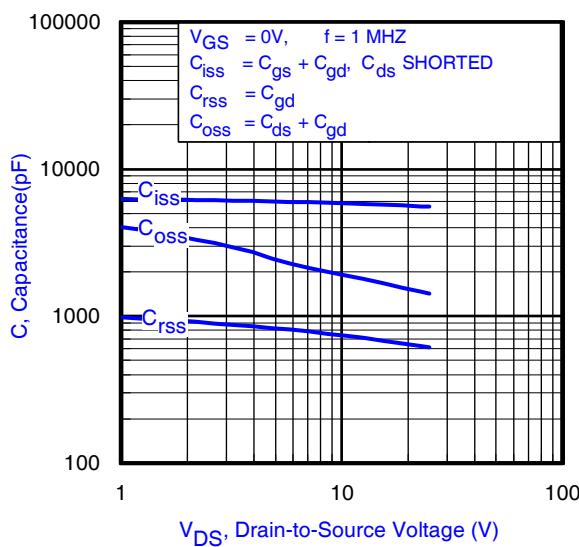


Fig 8. Typical Capacitance vs. Drain-to-Source Voltage

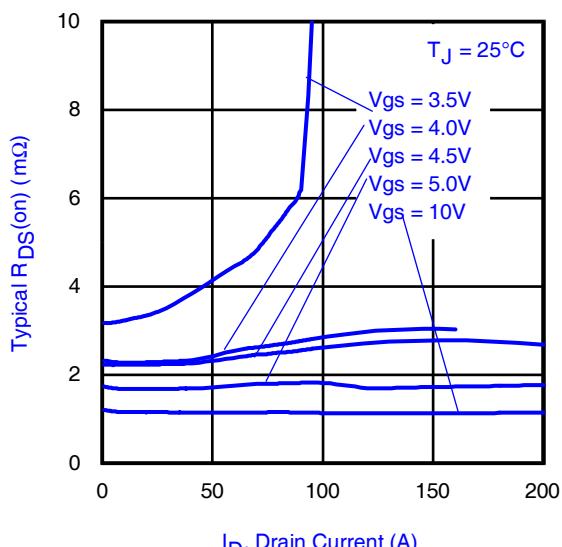


Fig 9. Typical On-Resistance vs. Drain Current and Gate Voltage

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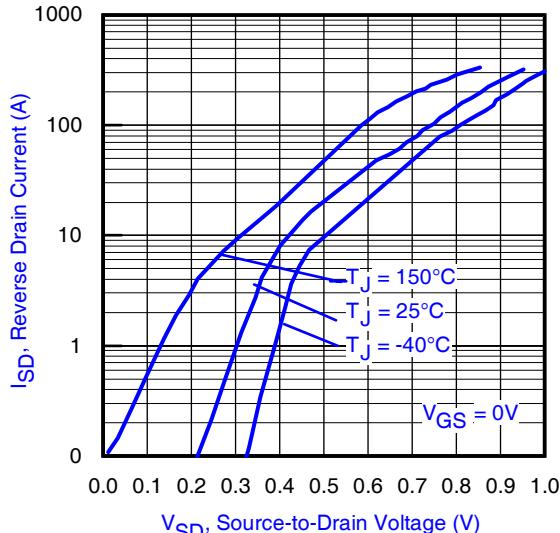


Fig 10. Typical Source-Drain Diode Forward Voltage

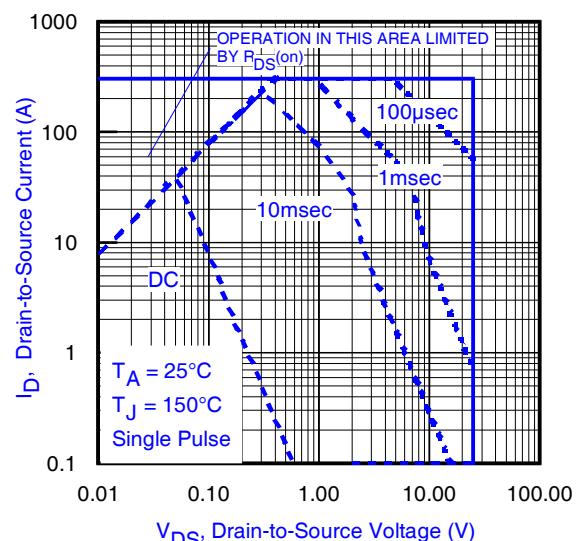


Fig 11. Maximum Safe Operating Area

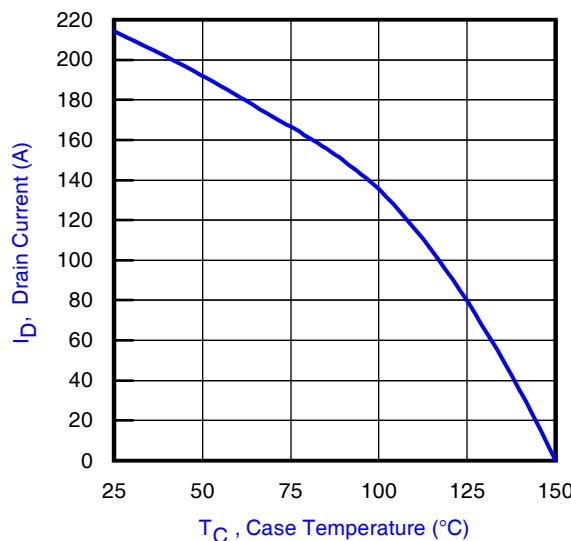


Fig 12. Maximum Drain Current vs. Case Temperature

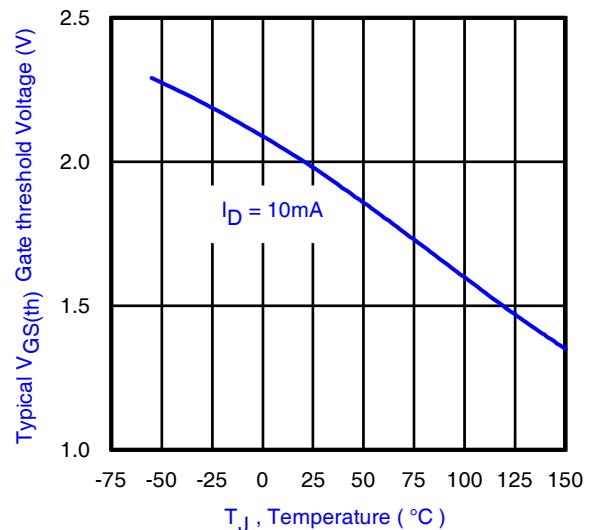


Fig 13. Typical Threshold Voltage vs. Junction Temperature

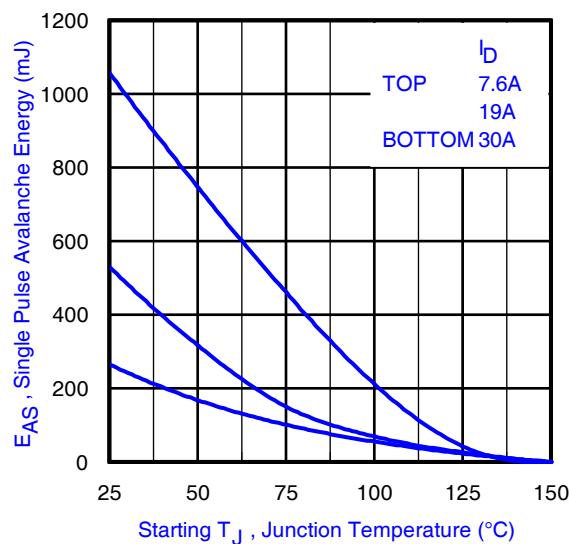


Fig 14. Maximum Avalanche Energy vs. Drain Current

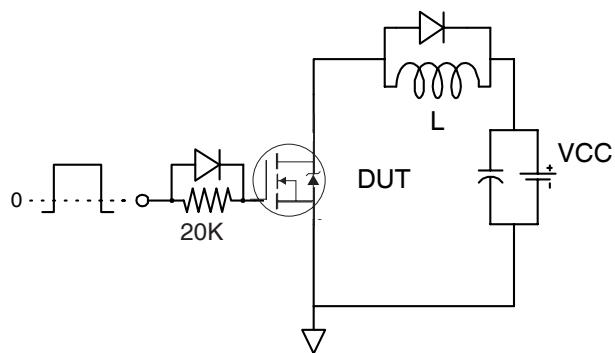


Fig 15a. Gate Charge Test Circuit

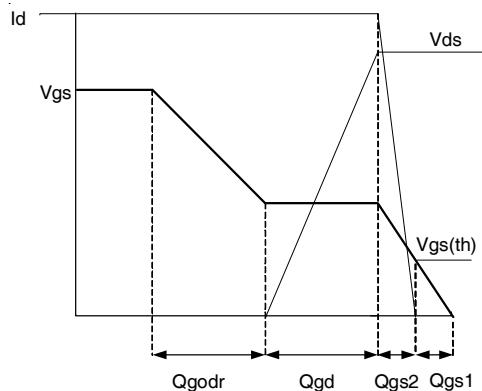


Fig 15b. Gate Charge Waveform

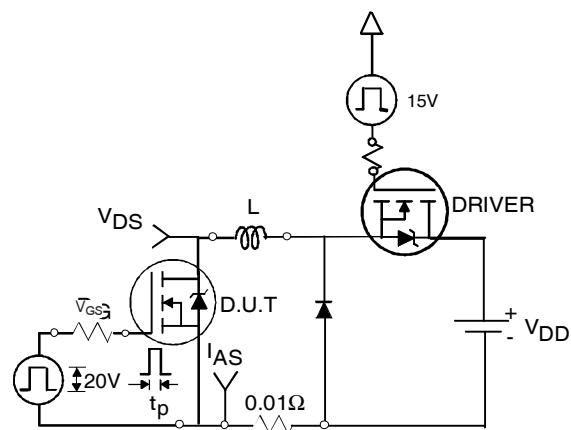


Fig 16a. Unclamped Inductive Test Circuit

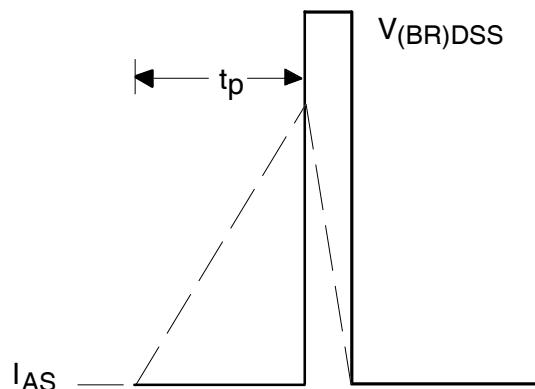


Fig 16b. Unclamped Inductive Waveforms

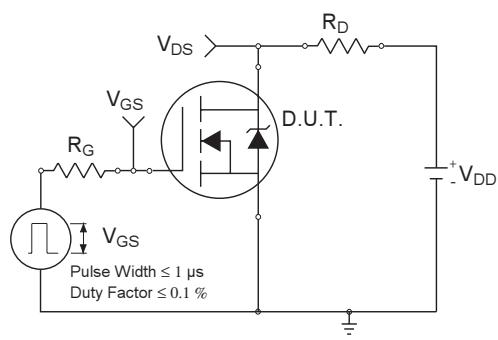


Fig 17a. Switching Time Test Circuit

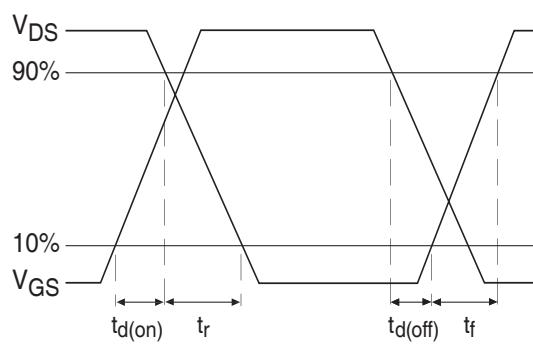


Fig 17b. Switching Time Waveforms

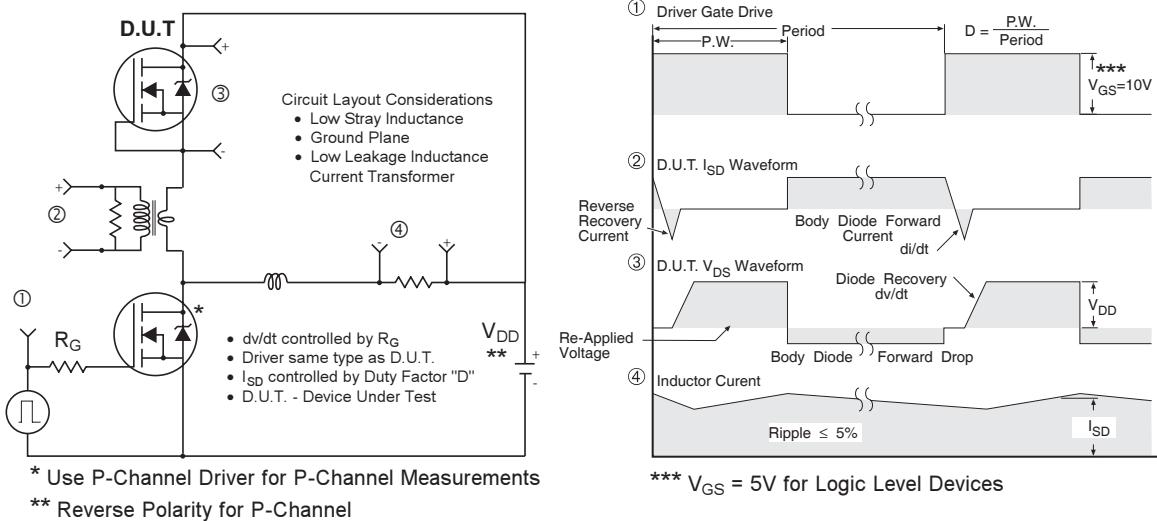
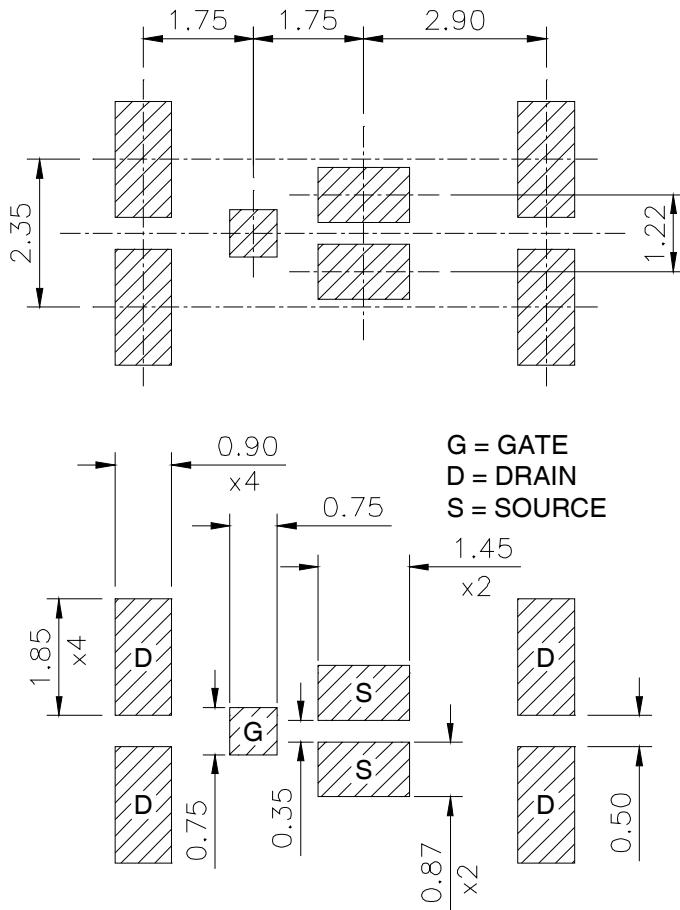


Fig 18. Diode Reverse Recovery Test Circuit for HEXFET® Power MOSFETs

DirectFET™ Board Footprint, MX Outline (Medium Size Can, X-Designation).

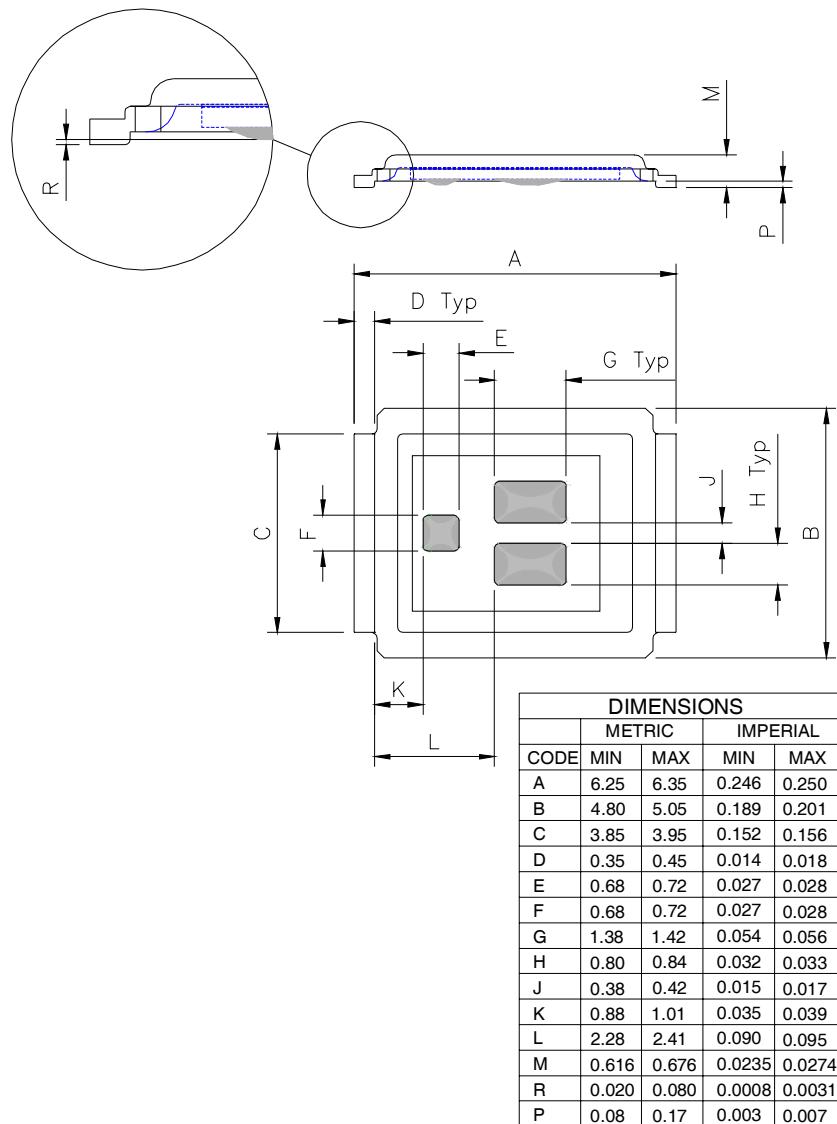
Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET.

This includes all recommendations for stencil and substrate designs.

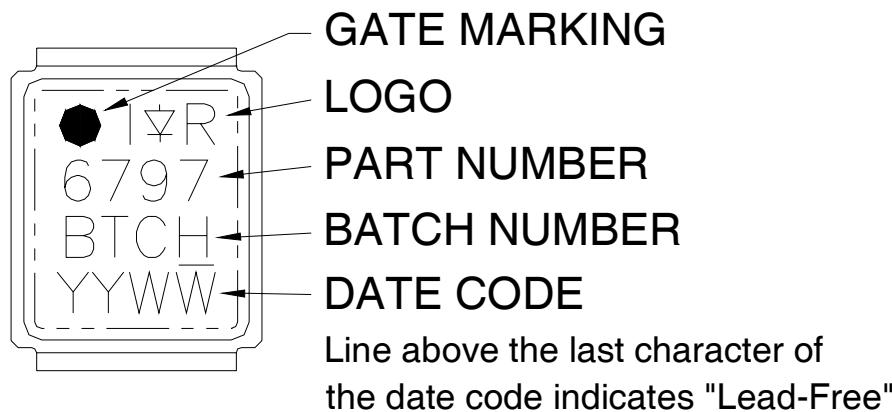


DirectFET™ Outline Dimension, MX Outline (Medium Size Can, X-Designation).

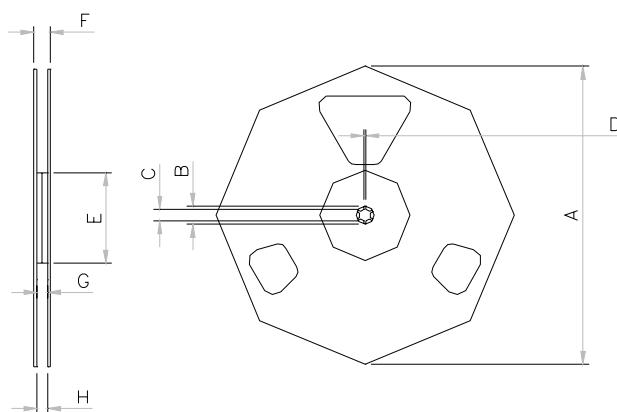
Please see DirectFET application note AN-1035 for all details regarding the assembly of DirectFET. This includes all recommendations for stencil and substrate designs.



DirectFET™ Part Marking



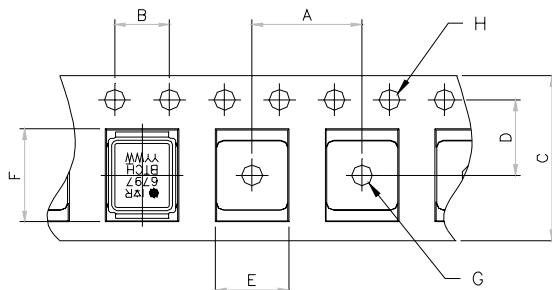
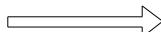
DirectFET™ Tape & Reel Dimension (Showing component orientation).



NOTE: Controlling dimensions in mm
Std reel quantity is 4800 parts. (ordered as IRF6797MTRPBF). For 1000 parts on 7" reel, order IRF6797MTR1PBF

REEL DIMENSIONS								
	STANDARD OPTION (QTY 4800)				TR1 OPTION (QTY 1000)			
	METRIC		IMPERIAL		METRIC		IMPERIAL	
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX
A	330.0	N.C.	12.992	N.C.	177.77	N.C.	6.9	N.C.
B	20.2	N.C.	0.795	N.C.	19.06	N.C.	0.75	N.C.
C	12.8	13.2	0.504	0.520	13.5	12.8	0.53	0.50
D	1.5	N.C.	0.059	N.C.	1.5	N.C.	0.059	N.C.
E	100.0	N.C.	3.937	N.C.	58.72	N.C.	2.31	N.C.
F	N.C.	18.4	N.C.	0.724	N.C.	13.50	N.C.	0.53
G	12.4	14.4	0.488	0.567	11.9	12.01	0.47	N.C.
H	11.9	15.4	0.469	0.606	11.9	12.01	0.47	N.C.

LOADED TAPE FEED DIRECTION



NOTE: CONTROLLING
DIMENSIONS IN MM

DIMENSIONS								
	METRIC		IMPERIAL		METRIC		IMPERIAL	
CODE	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX
A	7.90	8.10	0.311	0.319				
B	3.90	4.10	0.154	0.161				
C	11.90	12.30	0.469	0.484				
D	5.45	5.55	0.215	0.219				
E	5.10	5.30	0.201	0.209				
F	6.50	6.70	0.256	0.264				
G	1.50	N.C.	0.059	N.C.				
H	1.50	1.60	0.059	0.063				

Data and specifications subject to change without notice.
This product has been designed and qualified for the Consumer market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
TAC Fax: (310) 252-7903
Visit us at www.irf.com for sales contact information.03/09

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